Charge to spin conversion in epitaxial 2D CrTe₂/Bi₂Te₃ grown by MBE

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Abstract

2D CrTe₂ FM /Bi₂Te₃ TI heterostructures [1] are grown on 1 ML MoS₂ (WS₂)/sapphire substrates by MBE. Their physical properties are evaluated by in-situ RHEDD, STM and ARPES as well as Raman and XRD. A pure CrTe₂ phase is obtained at low T_g ~ 225 °C showing PMA and $T_c \sim 160$ K. Mixed $Cr_x Te_y$ phases, due to Cr self-intercalation are obtained at high $T_g \sim 500$ C with a T_c near or above 300K. In CrTe₂, the topological Hall effect is observed below 100 K, indicating the presence of skyrmions [2]. Spin torque second harmonic measurements show a large field-like (FL) torque which indicates charge-spin conversion arising from the topological surface states [3]. Partial magnetization reversal is observed at 150 K (Fig.2) in an AHE configuration, induced by current pulses of ~ 1×10^7 A/cm² passing through the Bi₂Te₃ TI.

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References	
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- [2] J. Chen et al., Nano Lett. 19, 6144 (2019)
- [3] P.M. Haney et al., *PRB* **87**, 174411 (2013)

Figures





Figure 1: In situ Surface analysis showing a pure 1x1 CrTe2 phase in the epitaxial film. Top: RHEED pattern; bottom: STM and fast Fourier transform pattern



Figure 2: Magnetization reversal in CrTe₂/Bi₂Te₃ obtained in an AHE configuration under current pulses through the Bi₂Te₃ topological insulator